2SA1674

Silicon PNP epitaxial planar type

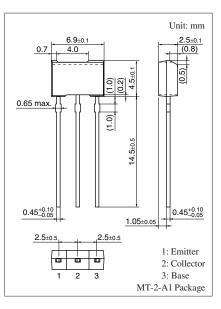
For low-frequency output amplification Complementary to 2SC4391

Features

- \bullet Low collector-emitter saturation voltage $V_{\mbox{CE(sat)}}$
- \bullet High collector-emitter voltage (Base open) V_{CEO}
- Allowing supply with the radial taping

Parameter	Symbol	Rating	Unit		
Collector-base voltage (Emitter open)	V _{CBO}	-80	V		
Collector-emitter voltage (Base open)	V _{CEO}	-80	V		
Emitter-base voltage (Collector open)	V _{EBO}	-5	V		
Collector current	I _C	-1	А		
Peak collector current	I _{CP}	-1.5	А		
Collector power dissipation *	P _C	1	W		
Junction temperature	Tj	150	°C		
Storage temperature	T _{stg}	-55 to +150	°C		





Note) *: Printed circuit board: Copper foil area of 1 cm² or more, and the board thickness of 1.7 mm for the collector portion

Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$

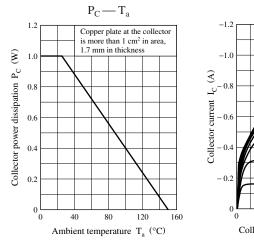
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-base voltage (Emitter open)	V _{CBO}	$I_{\rm C} = -10 \ \mu A, \ I_{\rm E} = 0$	-80			V
Collector-emitter voltage (Base open)	V _{CEO}	$I_{\rm C} = -1 {\rm mA}, I_{\rm B} = 0$	-80			V
Emitter-base voltage (Collector open)	V _{EBO}	$I_{\rm E} = -10 \ \mu A, \ I_{\rm C} = 0$	-5			V
Collector-base cutoff current (Emitter open)	I _{CBO}	$V_{CB} = -40 \text{ V}, I_E = 0$			- 0.1	μΑ
Forward current transfer ratio	h _{FE1} *2	$V_{CE} = -2 V, I_C = -100 mA$	120		340	
	h _{FE2} *1	$V_{CE} = -2 \text{ V}, I_{C} = -500 \text{ mA}$	60			
Collector-emitter saturation voltage *1	V _{CE(sat)}	$I_{\rm C} = -500 \text{ mA}, I_{\rm B} = -50 \text{ mA}$		- 0.2	- 0.3	V
Base-emitter saturation voltage *1	V _{BE(sat)}	$I_{\rm C} = -500 \text{ mA}, I_{\rm B} = -50 \text{ mA}$		- 0.85	-1.20	V
Transition frequency	f _T	$V_{CB} = -10 \text{ V}, I_E = 50 \text{ mA}, f = 200 \text{ MHz}$		120		MHz
Collector output capacitance	C _{ob}	$V_{CB} = -10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$		15	30	pF
(Common base, input open circuited)						

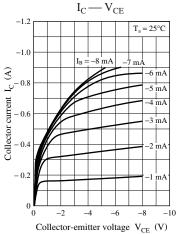
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

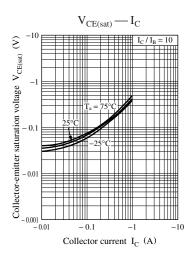
2. *1: Pulse measurement

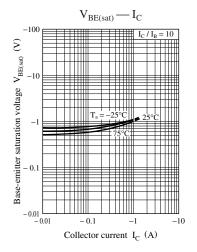
*2: Rank classification					
Rank	R	S			
h _{FE1}	120 to 240	170 to 340			

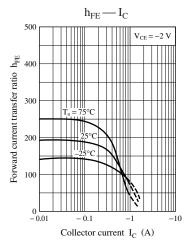
Panasonic

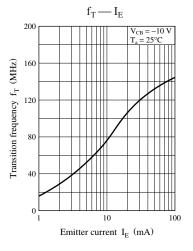


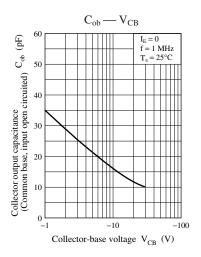












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